


<b>Search Notes</b>  	<b>Application/Control No.</b>  10688763	<b>Applicant(s)/Patent Under Reexamination</b>  YIP ET AL.
	<b>Examiner</b>  Wang, Ben C	<b>Art Unit</b>  2196

SEARCHED			
Class	Subclass	Date	Examiner
717	125 - combined with text search	11/27/2006	Ben C. Wang
345	581-681 - combined with text search	11/27/2006	Ben C. Wang
717	125 - combined with text search	5/20/2007	Ben C. Wang
717	128	9/17/2007	Ben C. Wang
715	772	9/17/2007	Ben C. Wang
715	967	9/17/2007	Ben C. Wang

SEARCH NOTES		
Search Notes	Date	Examiner
EAST class/subclass combined with text search; Google, IEEE, ACM Databases Search	11/27/2006	Ben C. Wang
Updated EAST, Google, IEEE, ACM Databases Search	5/20/2007	Ben C. Wang
Updated NPL search: IEEE, ACM Digital Library, and google.com	9/12/2007	Ben C. Wang
Updated East search: 717/128, 715/772, 967 class/subclass	9/17/2007	Ben C. Wang

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
717	135	9/12/2007	Ben C. Wang
717	128	9/17/2007	Ben C. Wang
715	772, 967	9/17/2007	Ben C. Wang